



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/734,419
Filing Date December 11, 2003
Inventor John T. Moore et al.
Assignee Micron Technology, Inc.
Group Art Unit 2815
Examiner Warren, Matthew E.
Attorney's Docket No. MI22-2463
Title: Semiconductor Wafer Assemblies Comprising Photoresist Over Silicon
Nitride Materials

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

To: Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: Jennifer J. Taylor, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on
the attached Form PTO-1449.

Citation of these references is respectfully requested.

A check in the amount of \$180.00 is enclosed to cover the fee specified
under 37 C.F.R. § 1.17(p).

Respectfully submitted,

Dated:

May 19, 2005

By:

Jennifer J. Taylor
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)ATTY. DOCKET NO.
MI22-2463SERIAL NO.
10/734,419APPLICANT
John T. Moore et al.FILING DATE
December 11, 2003GROUP
2815

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,756,634	06-2004	Helm et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Classes	Subclass	Translation	
							Yes	No
	AK							
	AL							
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AN	
	AO	
	AP	
EXAMINER	DATE CONSIDERED	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.